

| | | | |
|-----------------------------------|---------------------------------------|--|-------------|
| Notice of References Cited | Application/Control No. 10/664,211 | Applicant(s)/Patent Under Reexamination VERMA ET AL. | |
| | Examiner Walter L. Lindsay, Jr. | Art Unit 2812 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|----------------------|----------------|
| | A | US-6,239,011 | 05-2001 | Chen et al. | 438/595 |
| | B | US-6,764,884 | 07-2004 | Yu et al. | 438/157 |
| | C | US-6,399,440 | 06-2002 | Miao, Hui-Wen | 438/255 |
| | D | US-6,277,698 | 08-2001 | Ishida et al. | 438/299 |
| | E | US-6,238,987 | 05-2001 | Lee, Claymens | 438/305 |
| | F | US-6,074,922 | 06-2000 | Wang et al. | 438/303 |
| | G | US-6,103,559 | 08-2000 | Gardner et al. | 438/183 |
| | H | US-5,966,597 | 10-1999 | Wright, Peter J. | 438/197 |
| | I | US-5,731,239 | 03-1998 | Wong et al. | 438/296 |
| | J | US-6,271,087 | 08-2001 | Kinoshita et al. | 438/258 |
| | K | US-6,281,059 | 08-2001 | Cheng et al. | 438/200 |
| | L | US-6,194,299 | 02-2001 | Buynoski, Matthew S. | 438/592 |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.